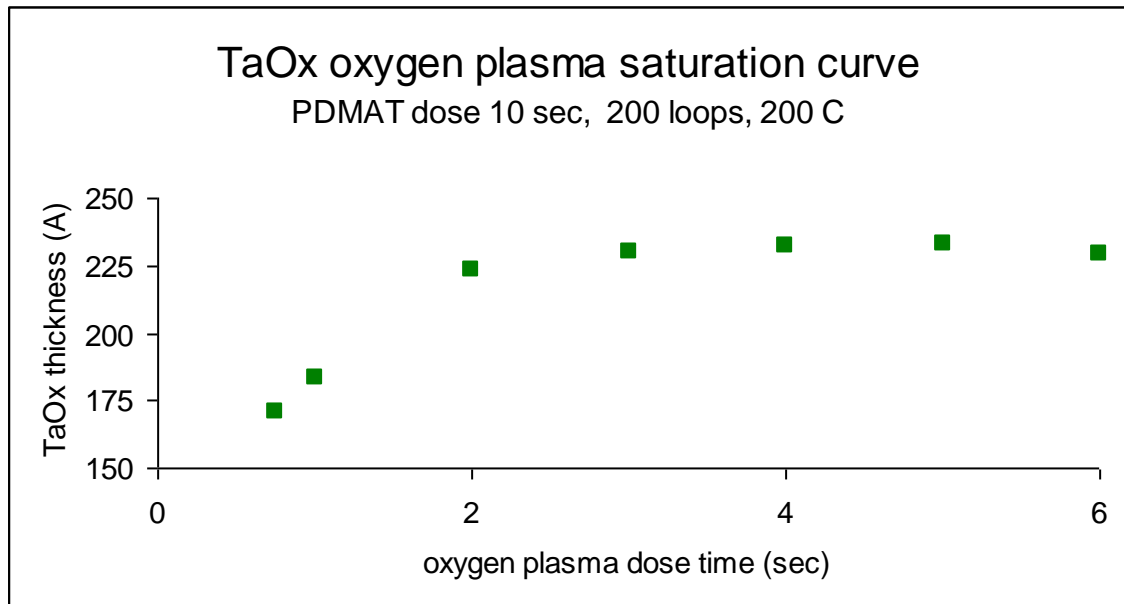
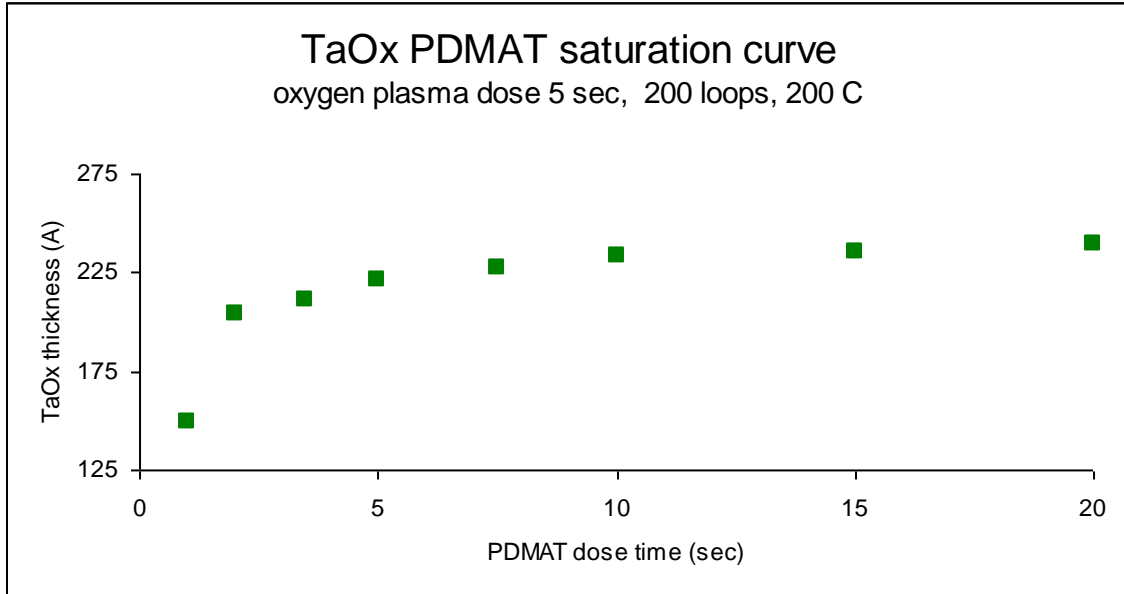
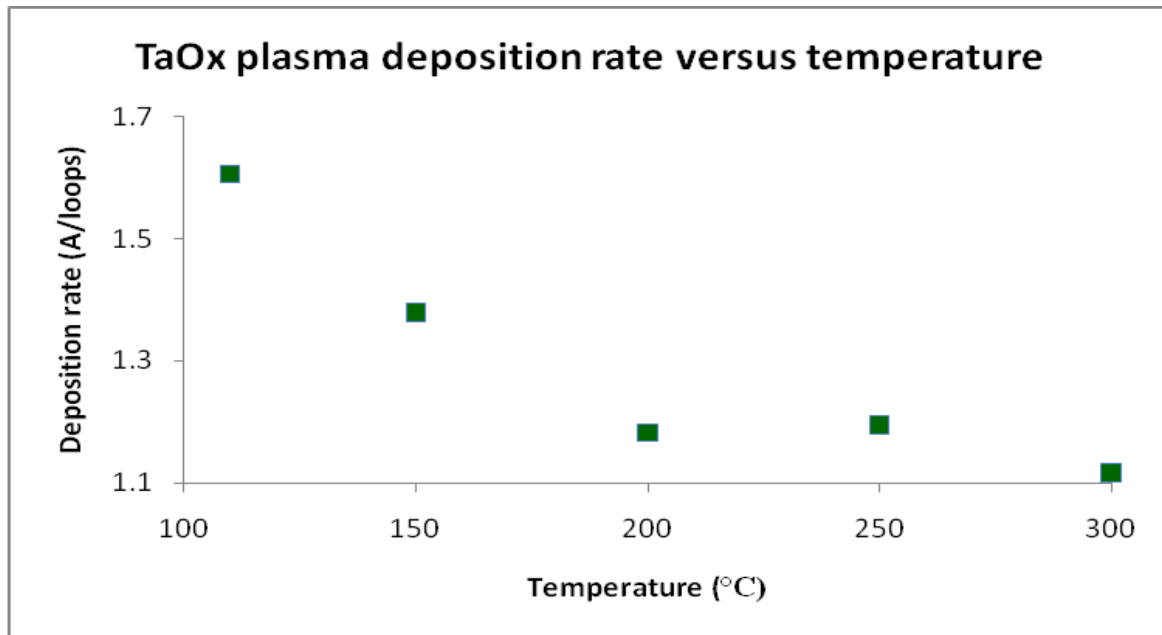
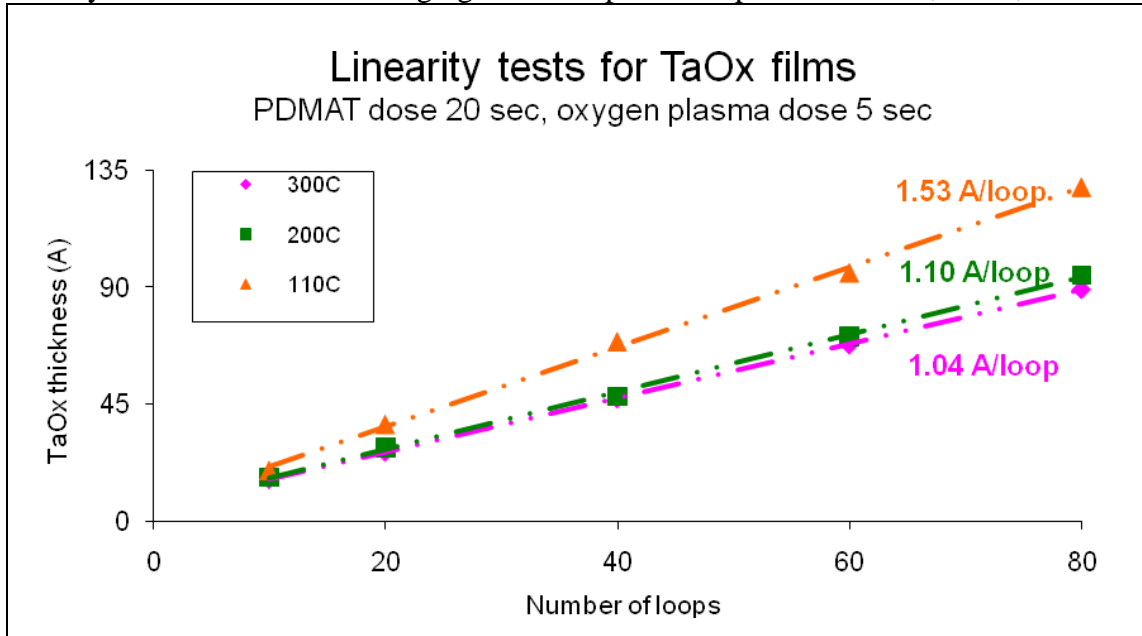


# ALD Ta<sub>2</sub>O<sub>5</sub> (TaOx) plasma characterization

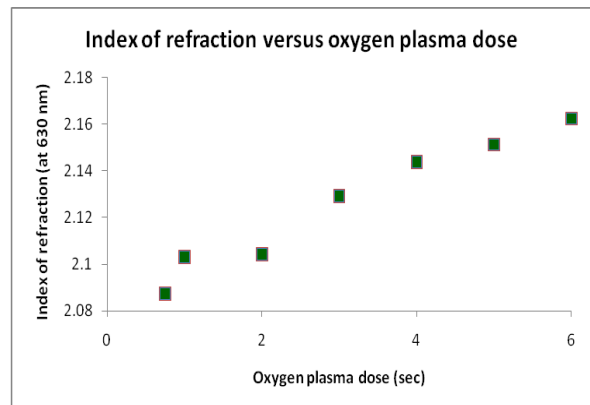
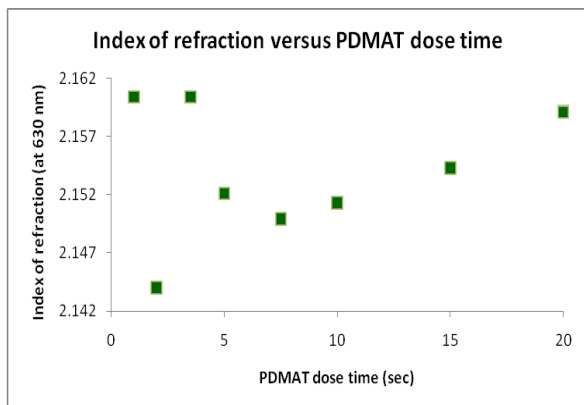
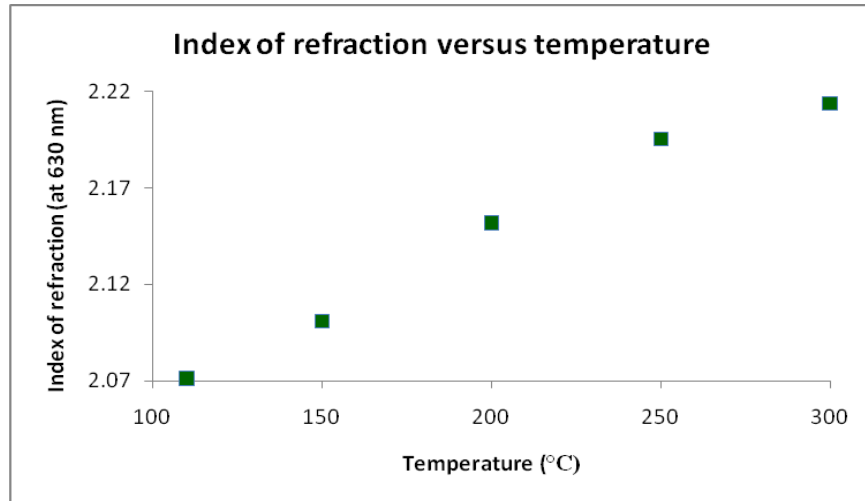
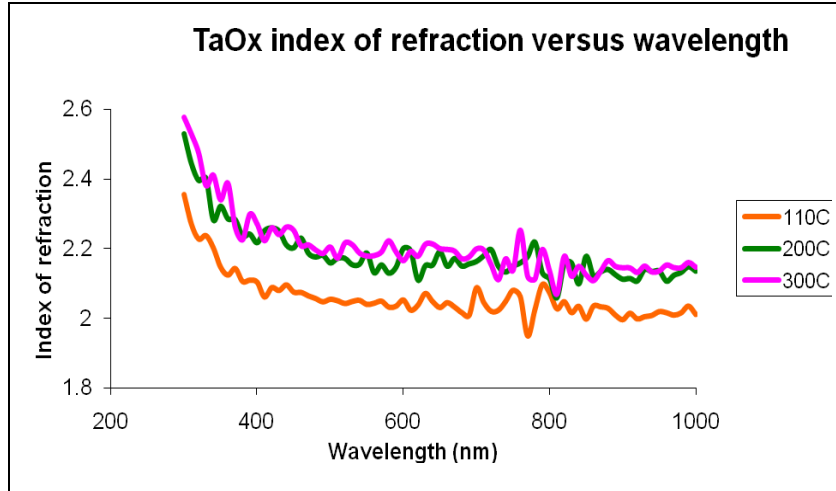
## 1. PDMAT precursor and oxygen plasma saturation plots



2. Linearity tests for TaOx films ranging 10-80 loops for temperatures 110C, 200C, and 300C



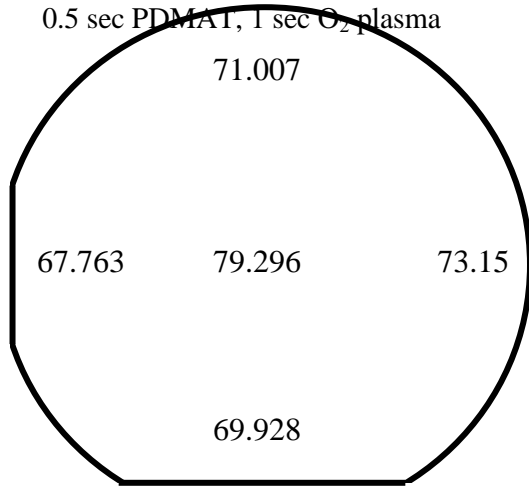
3. Index of refraction data for temperatures 110C, 200C, and 300C.



4. Film uniformity measurements (data collected using the Woollam ellipsometer)

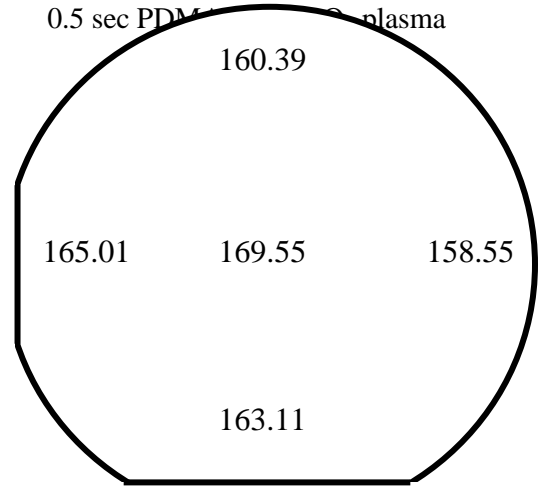
0.5 sec PDMAT, 1 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma



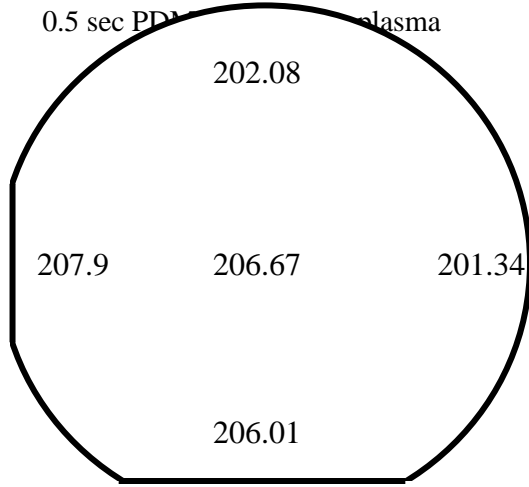
1 sec PDMAT, 1 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma



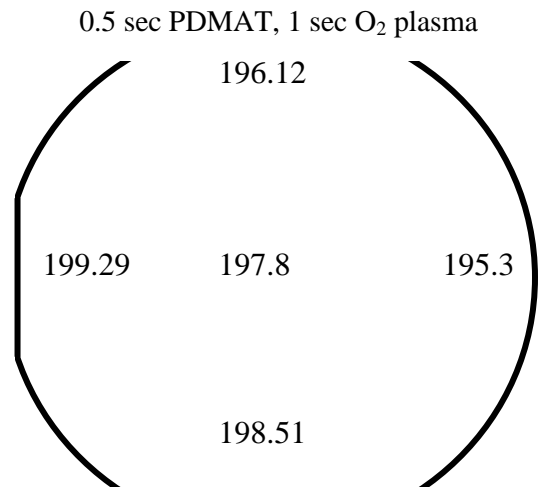
5 sec PDMAT, 1 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma



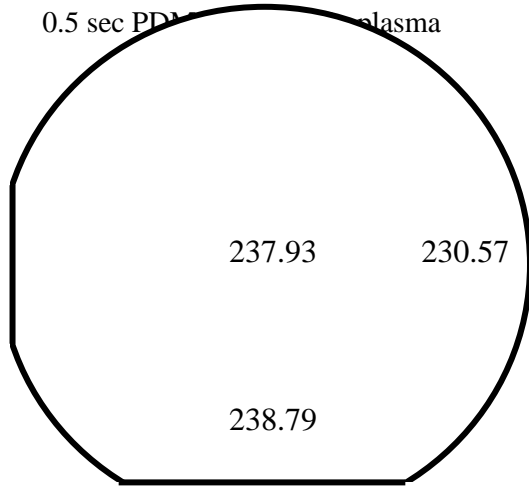
10 sec PDMAT, 1 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma



10 sec PDMAT, 2 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma



10 sec PDMAT, 6 sec oxygen plasma

0.5 sec PDMAT, 1 sec O<sub>2</sub> plasma

